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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				<i>Complete if Known</i>	
				Application Number	<u>10/552702</u> Concurrently
				Filing Date	
				First Named Inventor	Timothy J. N. CARTER
				Group Art Unit	
				Examiner Name	
				Confirmation No.	
				Sheet	1

[illegible]

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code. <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.

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Sheet	2	of	3	Attorney Docket Number	1768-138

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T <sup>6</sup>
		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
	AD	EP	0 049 918	A1	Douglas McQueen et al.	04-21-1982	
	AE	FR	2 715 226	A1	Universite De Reims Champagne-Ardenne	07-21-1995	✓
	AF	WO	90/13017	A1	Public Health Laboratory Service Board	11-01-1990	
Examiner Signature	/Paul Hyun/				Date Considered	09/21/2009	

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>
	AG	GIBSON, Ceri A., et al., "Kinetic factors in the response of piezo-optical chemical monitoring devices," <i>Sensors and Actuators B</i> , August 31, 1998, pp. 238-243, vol. 51, no. 1-3. Elsevier.Sequoia S.A., Lausanne, Switzerland.	
	AH	VISSER, Eric P., et al., "Measurement of thermal diffusion in thin films using a modulated laser technique: Application to chemical-vapor-deposited diamond films," <i>Journal of Applied Physics</i> , April 1, 1992, pp. 3238-3248, vol. 71, no. 7.	
	AI	WRIGHT, John D., et al., "Development of a piezo-optical chemical monitoring system," <i>Sensors and Actuators B</i> , August 31, 1998, pp. 121-130, vol. 51, no. 1-3. Elsevier.Sequoia S.A., Lausanne, Switzerland	
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